

**N - CHANNEL ENHANCEMENT MODE  
POWER MOS TRANSISTORS**

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub> ■
IRF730	400 V	1.0 Ω	5.5 A
IRF730FI	400 V	1.0 Ω	3.5 A
IRF731	350 V	1.0 Ω	5.5 A
IRF731FI	350 V	1.0 Ω	3.5 A
IRF732	400 V	1.5 Ω	4.5 A
IRF732FI	400 V	1.5 Ω	3.0 A
IRF733	350 V	1.5 Ω	4.5 A
IRF733FI	350 V	1.5 Ω	3.0 A

- HIGH VOLTAGE - FOR ELECTRONIC LAMP BALLAST
- ULTRA FAST SWITCHING
- EASY DRIVE - FOR REDUCED COST AND SIZE

**INDUSTRIAL APPLICATIONS:**

- ELECTRONIC LAMP BALLAST
- DC SWITCH

N - channel enhancement mode POWER MOS field effect transistors. Easy drive and very fast switching times make these POWER MOS transistors ideal for high speed switching applications. Applications include DC switch, constant current source, ultrasonic equipment and electronic ballast for fluorescent lamps.

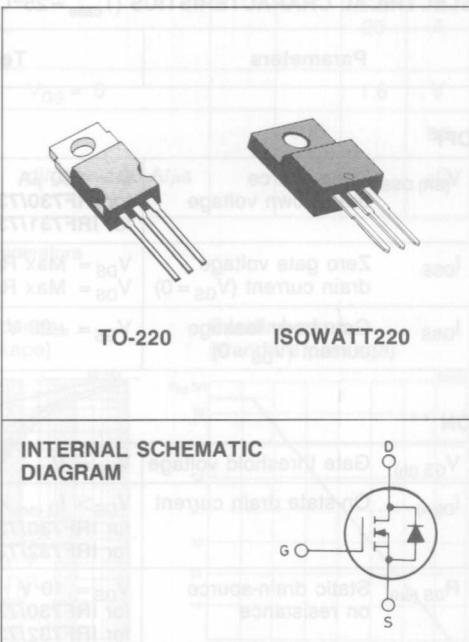
**ABSOLUTE MAXIMUM RATINGS**

	TO-220	IRF			
		730 730FI	731 731FI	732 732FI	733 733FI
V <sub>DSS</sub> *	Drain-source voltage (V <sub>GS</sub> = 0)	400	350	400	350
V <sub>DGR</sub> *	Drain-gate voltage (R <sub>GS</sub> = 20 kΩ)	400	350	400	350
V <sub>GS</sub>	Gate-source voltage			±20	V
I <sub>DM</sub> (•)	Drain current (pulsed)	20	20	16	16
I <sub>DLM</sub>	Drain inductive current, clamped (L = 100 μH)	20	20	16	16
I <sub>D</sub>	Drain current (cont.) at T <sub>c</sub> = 25°C	5.5	5.5	4.5	4.5
I <sub>D</sub>	Drain current (cont.) at T <sub>c</sub> = 100°C	3.5	3.5	3	3
I <sub>D</sub> ■	Drain current (cont.) at T <sub>c</sub> = 25°C	3.5	3.5	3	3
I <sub>D</sub> ■	Drain current (cont.) at T <sub>c</sub> = 100°C	2	2	1.8	1.8
P <sub>tot</sub> ■		TO-220			
Total dissipation at T <sub>c</sub> < 25°C		74	35		
Derating factor		0.59	0.28		
T <sub>stg</sub>	Storage temperature			-55 to 150	°C
T <sub>J</sub>	Max. operating junction temperature			150	°C

\* T<sub>J</sub> = 25°C to 125°C

(•) Repetitive Rating: Pulse width limited by max junction temperature.

■ See note on ISOWATT220 on this datasheet.



## THERMAL DATA

$R_{thj}$ - case	Thermal resistance junction-case	max	1.69	3.57	$^{\circ}\text{C}/\text{W}$
$R_{thc-s}$	Thermal resistance case-sink	typ	0.5	$^{\circ}\text{C}/\text{W}$	
$R_{thj-amb}$	Thermal resistance junction-ambient	max	80	$^{\circ}\text{C}/\text{W}$	
$T_L$	Maximum lead temperature for soldering purpose		300	$^{\circ}\text{C}$	

ELECTRICAL CHARACTERISTICS ( $T_{\text{case}} = 25^{\circ}\text{C}$  unless otherwise specified)

Parameters	Test Conditions	Min.	Typ.	Max.	Unit
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## OFF

$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage for IRF730/732/730FI/732FI for IRF731/733/731FI/733FI	$I_D = 250 \mu\text{A}$ $V_{GS} = 0$	400		V
$I_{\text{DSS}}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = \text{Max Rating}$ $V_{DS} = \text{Max Rating} \times 0.8$ $T_c = 125^{\circ}\text{C}$		250 1000	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 20 \text{ V}$		$\pm 500$	nA

## ON \*\*

$V_{GS\ (\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}$	$I_D = 250 \mu\text{A}$	2	4	V
$I_{D(\text{on})}$	On-state drain current	$V_{DS} > I_{D(\text{on})} \times R_{DS(\text{on})\ \text{max}}$ for IRF730/731/730FI/731FI for IRF732/733/732FI/733FI	$V_{GS} = 10 \text{ V}$	5.5 4.5		A
$R_{DS\ (\text{on})}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}$ for IRF730/731/730FI/731FI for IRF732/733/732FI/733FI	$I_D = 3.0 \text{ A}$		1.0 1.5	$\Omega$

## DYNAMIC

$g_{fs}$ **	Forward transconductance	$V_{DS} > I_{D(\text{on})} \times R_{DS(\text{on})\ \text{max}}$ $I_D = 3.0 \text{ A}$		2.9		mho
$C_{iss}$	Input capacitance				800	pF
$C_{oss}$	Output capacitance				300	pF
$C_{rss}$	Reverse transfer capacitance	$V_{DS} = 25 \text{ V}$ $V_{GS} = 0$	$f = 1 \text{ MHz}$		80	pF

## SWITCHING

$t_d\ (\text{on})$	Turn-on time	$V_{DD} = 175 \text{ V}$	$I_D = 3.0 \text{ A}$		30	ns
$t_r$	Rise time	$R_i = 15 \Omega$			35	ns
$t_d\ (\text{off})$	Turn-off delay time		(see test circuit)		55	ns
$t_f$	Fall time				35	ns
$Q_g$	Total Gate Charge	$V_{GS} = 10 \text{ V}$	$I_D = 5.5 \text{ A}$		35	nC
		$V_{DS} = \text{Max Rating} \times 0.8$	(see test circuit)			

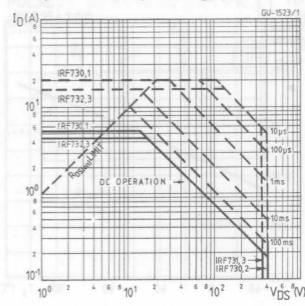
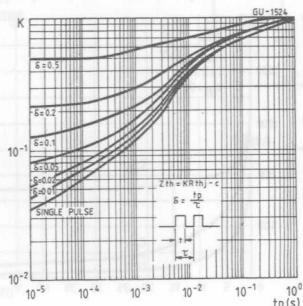
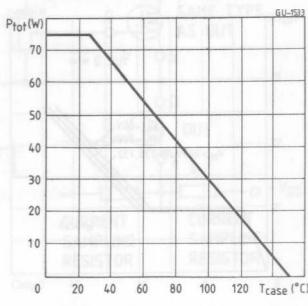
## ELECTRICAL CHARACTERISTICS (Continued)

Parameters	Test Conditions		Min.	Typ.	Max.	Unit
<b>SOURCE DRAIN DIODE</b>						
$I_{SD}$	Source-drain current				5.5	A
$I_{SDM} (\textcircled{*})$	Source-drain current (pulsed)				20	A
$V_{SD}$	Forward on voltage	$I_{SD} = 5.5 \text{ A}$	$V_{GS} = 0$		1.6	V
$t_{rr}$	Reverse recovery time	$T_j = 150^\circ\text{C}$		600		ns
$Q_{rr}$	Reverse recovered charge	$I_{SD} = 5.5 \text{ A}$	$di/dt = 100 \text{ A}/\mu\text{s}$	4		$\mu\text{C}$

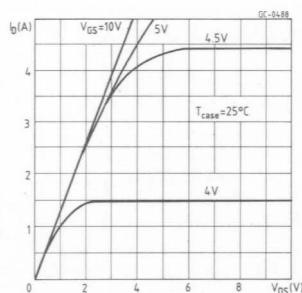
\*\* Pulsed: Pulse duration  $\leq 300 \mu\text{s}$ , duty cycle  $\leq 1.5\%$ 

(\*) Repetitive Rating: Pulse width limited by max junction temperature

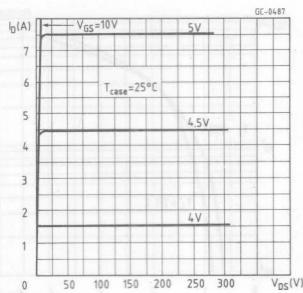
■ See note on ISOWATT220 in this datasheet

Safe operating areas  
(standard package)Thermal impedance  
(standard package)Derating curve  
(standard package)

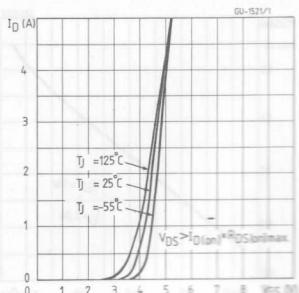
## Output characteristics



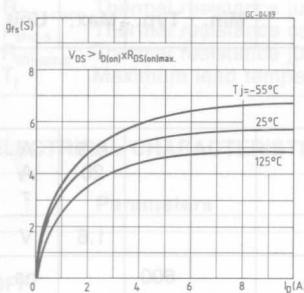
## Output characteristics



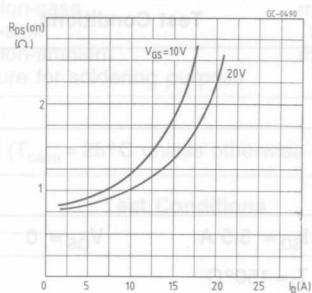
## Transfer characteristics



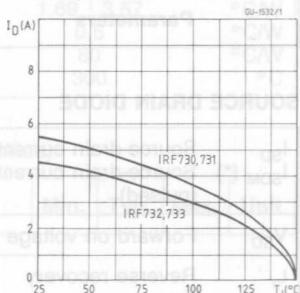
## Transconductance



## Static drain-source on resistance



## Maximum drain current vs temperature



## Drain-Source breakdown voltage

## Gate charge vs gate-source voltage

## Normalized drain current vs temperature

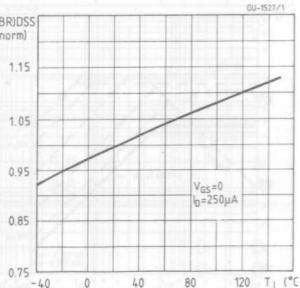
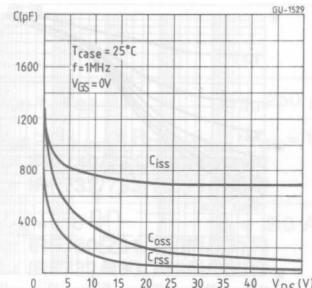
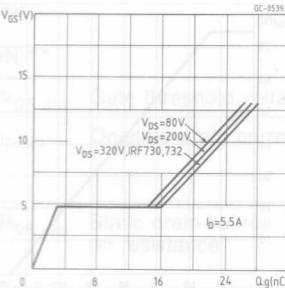
## Zero gate voltage drain current

## Capacitance variation

## Normalized breakdown voltage vs temperature

## Gate charge vs gate-source voltage

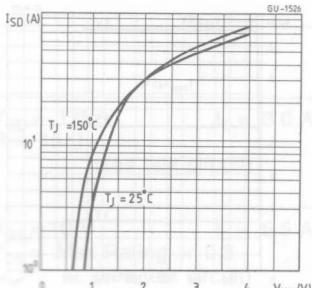
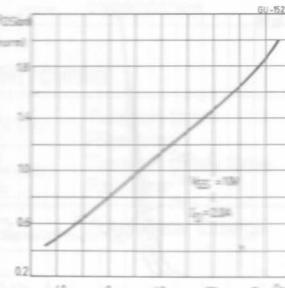
## (capacitance dependent)



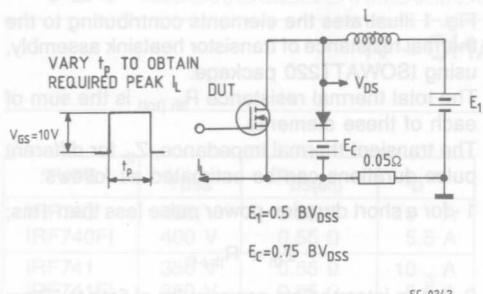
## Normalized drain conductance vs temperature

## Source-drain diode forward characteristics

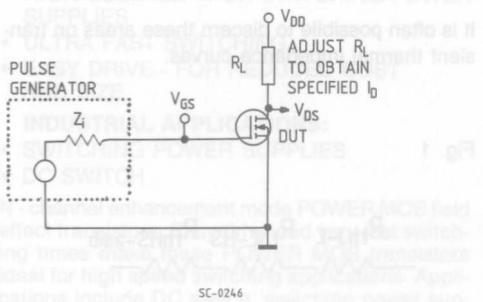
## Normalized on resistance vs temperature



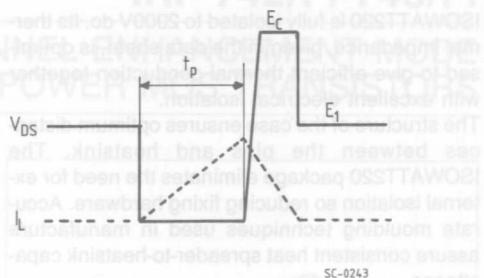
#### Clamped inductive test circuit



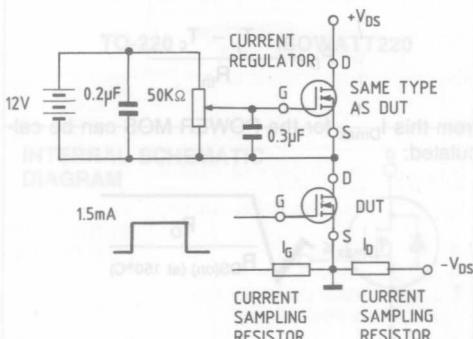
### Switching times test circuit



## Clamped inductive waveforms



#### Gate charge test circuit



## ISOWATT220 PACKAGE CHARACTERISTICS AND APPLICATION.

ISOWATT220 is fully isolated to 2000V dc. Its thermal impedance, given in the data sheet, is optimised to give efficient thermal conduction together with excellent electrical isolation.

The structure of the case ensures optimum distances between the pins and heatsink. The ISOWATT220 package eliminates the need for external isolation so reducing fixing hardware. Accurate moulding techniques used in manufacture assure consistent heat spreader-to-heatsink capacitance.

ISOWATT220 thermal performance is better than that of the standard part, mounted with a 0.1mm mica washer. The thermally conductive plastic has a higher breakdown rating and is less fragile than mica or plastic sheets. Power derating for ISOWATT220 packages is determined by:

$$P_D = \frac{T_j - T_c}{R_{th}}$$

from this  $I_{Dmax}$  for the POWER MOS can be calculated:

$$I_{Dmax} \leq \sqrt{\frac{P_D}{R_{DS(on)} \text{ (at } 150^\circ\text{C)}}}$$

## THERMAL IMPEDANCE OF ISOWATT220 PACKAGE

Fig. 1 illustrates the elements contributing to the thermal resistance of transistor heatsink assembly, using ISOWATT220 package.

The total thermal resistance  $R_{th(\text{tot})}$  is the sum of each of these elements.

The transient thermal impedance,  $Z_{th}$  for different pulse durations can be estimated as follows:

1 - for a short duration power pulse less than 1ms;

$$Z_{th} < R_{thJ-C}$$

2 - for an intermediate power pulse of 5ms to 50ms:

$$Z_{th} = R_{thJ-C}$$

3 - for long power pulses of the order of 500ms or greater:

$$Z_{th} = R_{thJ-C} + R_{thC-HS} + R_{thHS-amb}$$

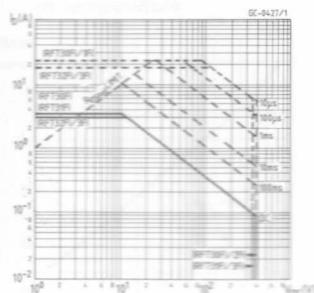
It is often possible to discern these areas on transient thermal impedance curves.

Fig. 1

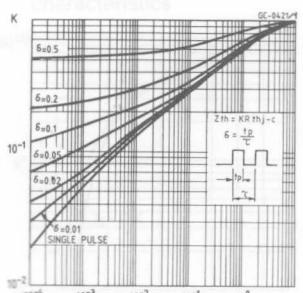
$$R_{thJ-C} \quad R_{thC-HS} \quad R_{thHS-amb}$$

## ISOWATT DATA

### Safe operating areas



### Thermal impedance



### Derating curve

